

Notice of References Cited	Application/Control No. 10/575,675	Applicant(s)/Patent Under Reexamination KHRUSHCHEV ET AL.	
	Examiner <i>QML</i> Quyen P. Leung	Art Unit 2874	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,563,995	05-2003	Keaton et al.	385/127
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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	O	JP 06224510 A	08-1994	Japan	KATO et al.	
	P					
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	English language translation of DE 101 55 492 completed 12/13/07.
	V	
	W	
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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